

**Search Notes**

Application/Control No.

10/528,549

Examiner

Jeff Natalini

Applicant(s)/Patent under  
Reexamination

FRANCE, GARRY GEORGE

Art Unit

2858

**SEARCHED**

Class	Subclass	Date	Examiner
324	639	11/14/2005	JWN
324	640	11/14/2005	JWN
73	73	5/24/2006	JWN
update	search	5/24/2006	JWN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
324	639	11/14/2005	JWN
324	640	11/14/2005	JWN
73	73	5/24/2006	JWN
.clm. text search		5/24/2006	JWN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East, 324/639, 640 and text search 324/637-641, and text search	11/14/2005	JWN
Non Patent literature search IEEE, Sceince Direct, and Measurment science tech for Stratified sampling w/ Microwave and simil	11/14/2005	JWN
Search class 73/73, and with text also text searched 73/29.01 and also many text searches	5/24/2006	JWN
.clm. interference search	5/24/2006	JWN
Also updated the search in the IEEE database	5/24/2006	JWN